Search Notes

•	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/806,617	SINGH ET AL.	
	Examiner	Art Unit	
	Brandon W. Bowers	2825	

SEARCHED					
Class	Subclass	Date	Examiner		
716	4	9/28/2006	ВВ		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East (see attached report)	9/28/2006	ВВ
IEEE (replicate/replication/duplicate/duplicati on and logic and FPGA)	9/28/2006	ВВ